

**Search Notes**

Application/Control No.

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Examiner

Benny Lee

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
333	238, 246	8/31/2005	BTL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR